Special Issue

Applications of Terahertz Sensing and Imaging

Message from the Guest Editors

Sensing and imaging technologies in the terahertz-wave region (0.1-10 THz) offer potential in a vast number of applications, including gas sensing, spectroscopy, material characterization, hydration monitoring, manufacturing process control, non-destructive testing. biomedical and biomolecular sensing and imaging. security, and other applications. Submissions are invited that address recent advances in terahertz (THz) sensing and imaging for practical applications, THz spectroscopy, measurement methods for sensing and imaging in the THz frequency range, novel THz photonic, electronic, and plasmonic devices, THz device and materials physics, simulation methods relevant to the THz regime, THz signal processing, and other related research. Both original research and review articles are invited.

Guest Editors

Prof. Dr. Matt Oehlschlaeger

Department of Mechanical, Aerospace, Nuclear Engineering Rensselaer Polytechnic Institute, Troy, NY 12180, USA

Prof. Dr. Mona M. Hella

Department of Electrical and Computer Systems Engineering, Rensselaer Polytechnic Institute, Troy, NY 12180, USA

Deadline for manuscript submissions

closed (20 November 2023)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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